

**Search Notes****Application/Control No.**

10/797,434

**Examiner**

Pablo N. Tran

**Applicant(s)/Patent under Reexamination**

RYU ET AL.

**Art Unit**

2618

**SEARCHED**

Class	Subclass	Date	Examiner
496	570	07/18/07	PL
63.1			
296			
67-13			
11A.2			
222			
223			
379	392-07		
3Y1	94-1		
92.2-94-9			
204	203-204		
226			
269		↓	↓

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Bart Weid	07/18/07	PL

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner